

STD70N02L STD70N02L-1

N-channel 24V - 0.0068Ω - 60A - DPAK - IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD70N02L	24V	<0.008Ω	60A
STD70N02L-1	24V	<0.008Ω	60A

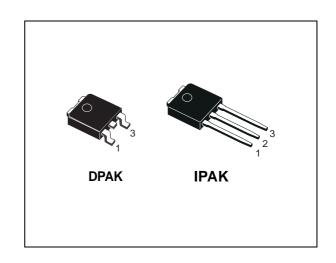
- R_{DS(ON)} * Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

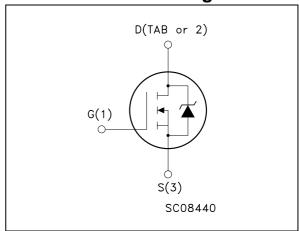
This series of products utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD70N02L-1	D70N02L	IPAK	Tube
STD70N02L	D70N02L	DPAK	Tape & reel

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{spike} (1)	Drain-source voltage rating	30	V
V _{DS}	Drain-source voltage (V _{GS} = 0)	24	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20k\Omega$)	24	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽²⁾	Drain current (continuous) at T _C = 25°C	60	Α
I _D	Drain current (continuous) at T _C = 100°C	42	А
I _{DM} ⁽³⁾	Drain current (pulsed)	240	А
P _{TOT}	Total dissipation at T _C = 25°C	60	W
	Derating factor	0.4	W/°C
E _{AS} (4)	Single pulse avalanche energy	280	mJ
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to 175	°C

- 1. Guaranted when external Rg=4.7 Ω and Tf<Tfmax
- 2. Value limited by wire bonding
- 3. Pulse width limited by safe operating area
- 4. Starting Tj =25°C, Id = 30A, V_{DD} = 15V

Table 2. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case Max	2.5	°C/W
Rthj-amb	Thermal resistance junction-amb Max	100	°C/W
T _I	Maximum lead temperature for soldering purpose	275	°C

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2 Electrical characteristics

(Tcase =25°C unless otherwise specified)

Table 3. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 25 \text{mA}, V_{GS} = 0$	24			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 20V, V _{DS} = 20V,Tc = 125°C			1 10	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.8		V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 30A$ $V_{GS} = 5V, I_D = 15A$		0.0068 0.090	0.008 0.014	Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15V, I_{D} = 30A$		27		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =16V, f=1MHz, V _{GS} =0		1400 400 55		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =10V, I_{D} = 60A V_{GS} =10V (see Figure 15)		24 5 3.4	32	nC nC nC
R _G	Gate input resistance	f=1MHz Gate DC Bias =0 test signal level =20mV open drain	0.5	1.5	3	Ω
Q _{OSS} ⁽²⁾	Output charge	V _{DS} =16V, V _{GS} =0V		9.4		nC

^{1.} Pulsed: pulse duration = 300µs, duty cycle 1.5%

^{2.} $Q_{oss.} = C_{oss} * D Vin, C_{oss} = C_{gd} + C_{gd.}$ (see *Appendix A*)

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(on)}	Turn-on delay time	V _{DD} =10V, I _D =30A,		10		ns
t _r	Rise time	$R_{G}=4.7\Omega, V_{GS}=10V$		130		ns
t _{d(off)}	Turn-off delay time	(see Figure 17)		27		ns
t _f	Fall time	(See Figure 17)		16	21.6	ns

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current (pulsed)				50 200	A A
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} =30A, V _{GS} =0			1.3	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} =60A, di/dt = 100A/μs, V _{DD} =20V, Tj=150°C (see Figure 20)		36 36 2		ns nC A

^{1.} Pulsed: pulse duration = 300µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

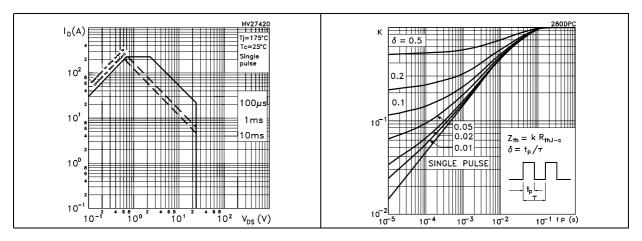


Figure 3. Output characterisics

Figure 4. Transfer characteristics

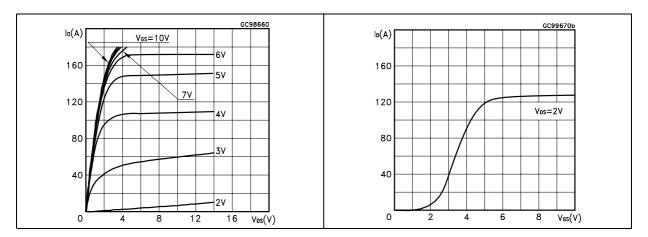
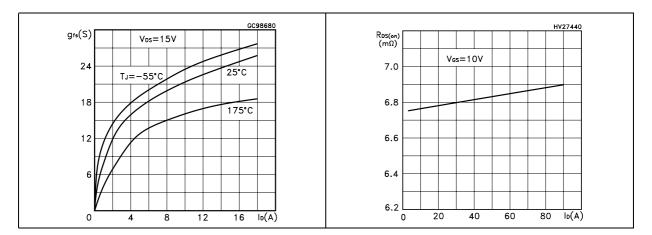


Figure 5. Transconductance

Figure 6. Static drain-source on resistance



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Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

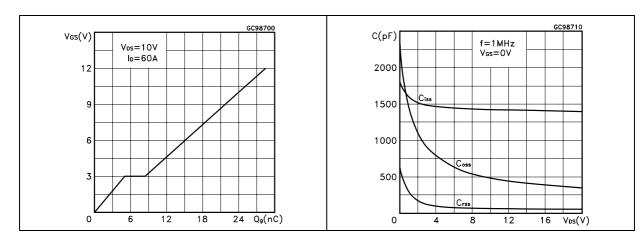


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

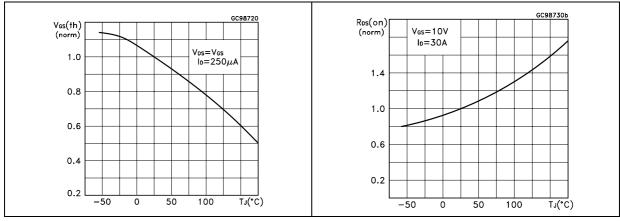
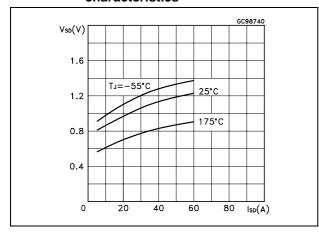


Figure 11. Source-drain diode forward characteristics

Figure 12. Normalized B_{VDSS} vs temperature



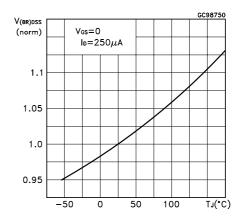
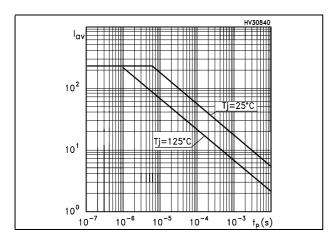


Figure 13. Allowable I_{AV} vs time in avalanche



The previous curve gives the single pulse safe operating area for unclamped inductive loads, under the following conditions:

$$P_{D(AVE)} = 0.5*(1.3*B_{VDSS}*I_{AV})$$

Where:

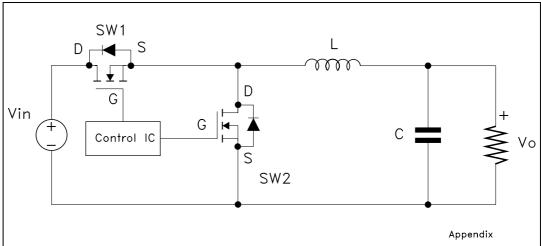
I_{AV} is the allowable current in avalanche

 $P_{D(AVE)}$ is the average power dissipation in avalanche (single pulse)

t_{AV} is the time in avalanche

Appendix A

Figure 14. Synchronous buck converter



The power losses associated with the FETs in a Synchronous Buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the wotking temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

Very low RDS(on) to reduce conduction losses

Small Qgls to reduce the gate charge losses

Small Coss to reduce losses due to output capacitance

Small Qrr to reduce losses on SW1 during its turn-on

The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source voltage to avoid the cross conduction phenomenon.

The high side (SW1) device requires:

Small Rg and Lg to allow higher gate current peak and to limit the voltage feedback on the gate

Small Qg to have a faster commutation and to reduce gate charge losses

Low RDS(on) to reduce the conduction losses

Table 7. Power losses

		High side switch (SW1)	Low side switch (SW2)
P _{conduction}		$R_{DS(on)} \bullet I_L^2 \bullet \delta$	$R_{DS(on)} \bullet I_L^2 \bullet (1 - \delta)$
P _{switching}		$V_{in} \bullet (Q_{gsth(SW1)} + Q_{gd(SW1)}) \bullet f \bullet \frac{I_L}{I_g}$	Zero voltage switching
P _{diode}	recovery	Not applicable	$^{1}V_{in} \bullet Q_{rr(SW2)} \bullet f$
diode	conduction	Not applicable	$V_{f(SW2)} \bullet I_L \bullet t_{deadtime} \bullet f$
P _{gate(Qg)}		$Q_{g(SW1)} \bullet V_{gg} \bullet f$	$Q_{gls(SW2)} \bullet V_{gg} \bullet f$
P _{Qoss}		$\frac{V_{in} \bullet Q_{oss(SW1)} \bullet f}{2}$	$\frac{V_{in} \bullet Q_{oss(SW2)} \bullet f}{2}$

Table 8. Power losses parameters

Paramter	Meaning
d	Duty-cycle
Q _{gsth}	Post threshold gate charge
Q _{gls}	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate driver losses
P _{Qoss}	Output capacitance losses

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3 Test circuits

Figure 15. Switching times test circuit for resistive load

Figure 16. Gate charge test circuit

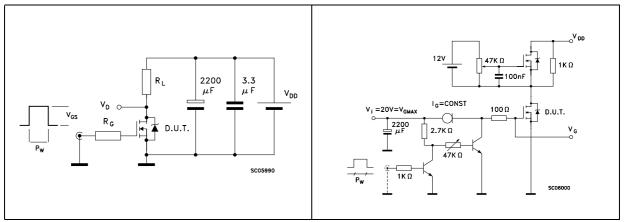


Figure 17. Test circuit for inductive load switching and diode recovery times

Figure 18. Unclamped inductive load test circuit

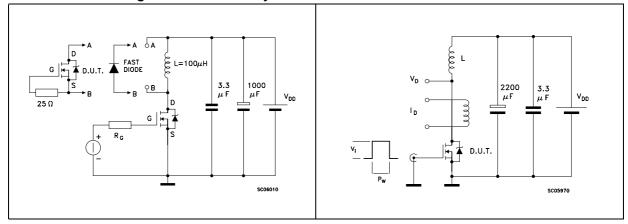
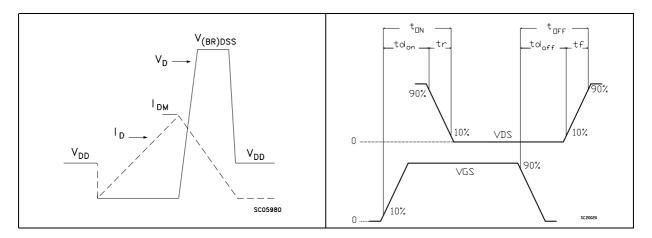


Figure 19. Unclamped inductive waveform

Figure 20. Switching time waveform

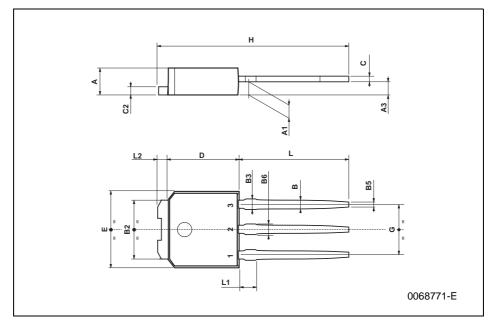


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

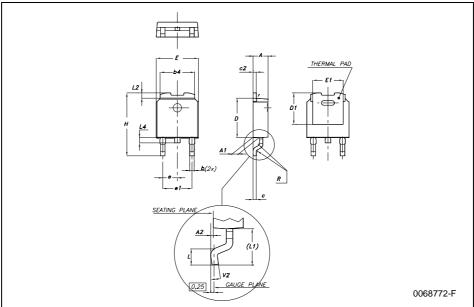
TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
Е	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



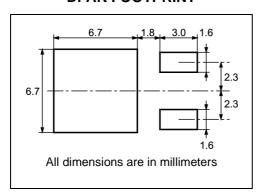
DPAK MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°

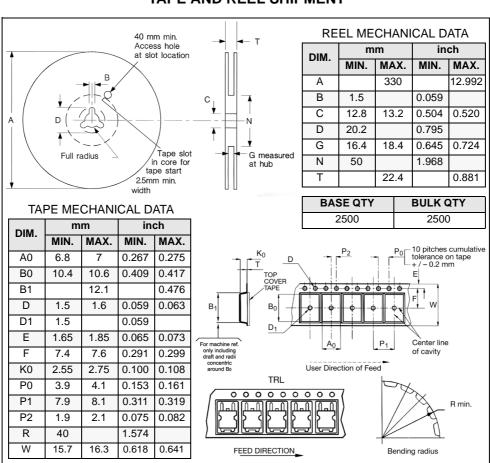


5 Package mechanical data

DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



6 Revision history

Table 9. Revision history

Date	Revision	Changes	
29-Aug-2005	1	First release	
02-Dec-2005	2	Modified Appendix A	
07-Apr-2006	3	New template	
03-May-2006	4	New value in Table 3, new curve (see Figure 13)	

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